

IN THE CLAIMS:

A1
AD
B1
Sub C1
A2

1 1. (Amended) A probe apparatus for testing a circuit chip, said probe apparatus
2 comprising a probe group having two or more probes within a guiding boundary
for independently conductively contacting a single terminal of said circuit chip.

1 12. (Amended) The method of claim 11, wherein said contacting is provided by said
2 group including a first, a second and a third of said probes, wherein said recognizing
3 includes recognizing a first, second and a third path resistance corresponding to said
4 first, second and said third of said probes, and wherein said deriving includes deriving
5 an absolute value of a first, second and third operational signal path resistance
6 corresponding to said first, second and said third path resistance.